



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#4  
pre. amt 9  
KDuncan  
9/9/02

Applicant : Mani SOMA et al.  
Art Unit :  
Serial No.: 10/033,188  
Examiner :  
Filed : October 25, 2001  
Title : Clock Skew Measurement Device and Measurement Method

Assistant Commissioner for Patents  
Washington, DC 20231

**PRELIMINARY AMENDMENT**

Dear Sir:

Prior to examination on the merits, please amend the application as follows and consider the included remarks.

**IN THE DRAWINGS:**

Please find enclosed formal drawings for this application. A separate letter to the official draftsman is also enclosed.

**IN THE SPECIFICATION:**

Please amend the specification as follows. Marked-up versions of the amended paragraphs are attached.

In the paragraph beginning on page 9, line 32:

a1 Fig. 6B shows exemplary timing jitter sequence  $\Delta\phi^k[n]$  of a clock  $CLK_k$  to be measured.

In the paragraph beginning on page 10, line 6:

a2 Fig. 11 shows an exemplary instantaneous phase  $\phi(t)$ . The discontinuities at  $-\Pi$  and  $+\Pi$  are observed.

In the paragraph beginning on page 10, line 8:

a3 Fig. 12 shows an unwrapped instantaneous phase  $\phi(t)$ . The discontinuities are removed.